Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/666,147	DEB ET AL.
Examiner	Art Unit

2856

Helen C. Kwok

SEARCHED				
Class	Subclass	Date	Examiner	
73	504.04	5/5/2005	нк	
73	504.12	5/5/2005	нк	
73	504.13	5/5/2005	нк	
73	504.14	5/5/2005	нк	
73	504.15	5/5/2005	нк	
73	514.32	5/5/2005	нк	
73	1.37	5/5/2005	НК	
73	1.38	5/5/2005	нк	
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INTERFERENCE SEARCHED					
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